

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet	4	Λf	2		

	Complete if Known
Application Number	10/808,774
Filing Date	March 24, 2004
First Named Inventor	Oeda, Takahashi
Art Unit	2162
Examiner Name	Jean M. Corrielus
Attorney Docket Number	16869P-009910US

	U.S. PATENT DOCUMENTS+							
		Document Number						
Examiner Initials*	Cite No.1	Number Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
9	1	6,509,828	01-21-2003	Bolavage et al.				
3	2	2002/0029224	03-07-2002	Carlsson				
4	3	6,167,405	12-26-2000	Rosensteel et al.				
Dec	4	6,122,630	09-19-2000	Strickler et al.				
Qc	5	5,884,028	03-16-1999	Kindell et al.				
JA-	6	5,831,985	11-03-1998	Sandorfi et al.				
CH	7	5,649,168	07-15-1997	Huang et al.				
De	8 -	5,630,067	05-13-1997	Kindell et al.				
Um	9	5,479,656	12-26-1995	Rawlings, til				
CHIR	10	5,457,793	10-10-1995	Elko et al.				
CHA	11	5,006,978	04-09-1991	Neches				
(MX	12	4,585,516	04-29-1986	Com et al.				
JK.	13	4,464,223	08-07-1984	Gorin.				
		1						

FOREIGN PATENT DOCUMENTS								
Examiner Cite No.1	Foreign Patent Document				Nome of Detector or	Pages, Columns, Lines,	Γ	
	Country Code ³	Number ⁴ Kind	Code ⁶ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear	τ°	
A.	14	PCT	WO99/54805	Α	10-28-1999	Sun Micraystems	•	
4	15	EP.	0869438	Α	10-07-1998	Hitachi, Ltd.		
0	16	PCT	WO98/35291	Α	08-13-1998	New Frame Corp.		
4	17	PCT	WO97/35269	Α	09-25-1997	EMC Corp.		
91								1

Examiner	1			Date		
Signature	Loan	μ.	Cornelis	Considered	6-19-05	

EXAMINER: Initially reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. Applicant's unique citation designation number (optional). Kind Codes of U.S. Patent Documents at www.uspic.gov or MPEP 901.04. Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. Nich indicated on the document under WIPO Standard ST. 18 if possible. Applicant is to place a check mark here if English language Translation is attached.

Substitute for form 1449B/PTO Complete if Known Application Number 10/808,774 INFORMATION DISCLOSURE Filing Date March 24, 2004 STATEMENT BY APPLICANT First Named Inventor Oeda, Takahashi Art Unit 2162 (use as many sheets as necessary) Examiner Name Jean.M. Corrielus Sheet Attomey Docket Number 16869P-009910US

		NON PATENT LITERATURE DOCUMENTS				
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the iter (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
Ju	18	"SAN Basics: A Technical White Paper from MetaStor Storage Solutions," LSI Logic Corporation Milpitas, CA (September 1999).				
Air.	19	"Tegal says TEL enjoined from selling etchers with dual-frequency technology," Semiconductor Business News, http://seminews.com/sbn/sbnh2/news/19990901a1.shtml (September 1999).				
Ay-	20	SINGER "The Challenge: Automating the Industry," Technical Program Proceedings Semicon / West 1984 San Mateo, California pp. 272-275 (May 1984).				
gu-	21	ZAJAC et al. "Automated Plasma Etch Systems for VLSI," Technical Program Proceedings Semicon / West 1984 San Mateo, California pp 27-35. (May 1984).				
du	22	ZAJAC et al. "Multi-Electrode Plasma Etching." Tegal Process Review, pp. 1-3, Tegal Corp. Petaluma, CA (May 1984).				
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Examiner Signature	Jean	И.	Parches	Date Considered	6-19-05
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